KLA-Tencor Surfscan 6220
Non-Patterned Wafer Particle Measurement System

SN 1097-306

- Currently Configured for 200mm Wafer Sizes
- Configurable for 50mm-200mm Wafer Sizes
- MFG Date: 1997
- Cassette Interface:
  - (2) Open Cassette Stations
- Operating System: Windows 95
- Features:
  - .10um Defect Sensitivity
  - Defect Map and Histogram
  - Haze Map and Histogram with Zoom
  - Argon Ion Laser (488nm)
  - Unique Scattering Microscope
  - 2D Signal Integration
  - 50um Spatial Resolution
  - Printer Parallel Port
- Options:
  - Exhaust Blower with system
  - Original monitor replaced w/Flat Screen (mounted externally on front)
- Facilities
  - HVAC: 500mm (20 in) of Hg at a flow rate of 0.236 l/s (0.5 cfm)
  - Power (Main): 208V, 30A, 1 Phase, 60 Hz
  - Power (Blower): 115 V
- Missing Parts/Damage:
  - Original Silicon Tile reported as bad, a new replacement is included with the tool

Interested parties may contact Matt Hayes at Macquarie Electronics for additional information at (408) 965-3863 or matt.hayes@macquarie.com.

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